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BIBDATASHEET

CONFIRMATION NO. 5475

SERIAL NUMBER 10/632,273	FILING DATE 07/31/2003 CLASS 324 RULE			GROUP ART UNIT 2829			ATTORNEY DOCKET NO. MI22- 2379		
APPLICANTS									
Warren M. Farnworth, Nampa, ID;									
Malcolm Grief, Boise, ID;									
** CONTINUING DATA **** This application is a DIV of 10/057,711 01/24/2002 PAT 6,670,819 which is a DIV of 09/411,139 10/01/1999 PAT 6,657,450 which is a DIV of 09/267,990 03/12/1999 PAT 6,380,754 which is a DIV of 08/895,764 07/17/1997 PAT 6,127,195 which is a CON of 08/621,157 03/21/1996 ABN which is a CON of 08/206,747 03/04/1994 PAT 5,523,697 which is a DIV of 08/116,394 09/03/1993 PAT 5,326,428 **FOREIGN APPLICATIONS*** **FOREIGN APPLICATIONS*** **FOREIGN FILING LICENSE GRANTED **10/28/2003									
Foreign Priority claimed	□ yes ⊠no		STATE OR	SHE	ETS	TOTAL	INDEPENDENT		
35 USC 119 (a-d) conditions met yes no Met after Allowance Verified and Acknowledged Examiner's Signature Initials			COUNTRY ID	DRAWING CL		CLAIMS 11	CLAIMS 1		
ADDRESS 021567 WELLS ST. JOHN P.S. 601 W. FIRST AVENUE, SUITE 1300 SPOKANE , WA 99201									
TITLE Method and apparatus for testing semiconductor circuitry for operability and method of forming apparatus for testing semiconductor circuitry for operability									
					☐ All Fees				
FILING FEE FEES:	3: Authority has been given in Paper			I⊨	1.16 Fees (
No	Noto charge/credit DEPOSIT ACCOUNT RECEIVED No for following:					☐ 1.17 Fees (Processing Ext. of time) ☐ 1.18 Fees (Issue)			
926 INC IOI IO/IOWING.					☐ Other				
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